## **IGBT**

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss.

#### **Features**

- Optimized for Very Low V<sub>CEsat</sub>
- Low Switching Loss Reduces System Power Dissipation
- Soft Fast Reverse Recovery Diode
- 5 µs Short-Circuit Capability
- These are Pb-Free Devices

#### **Typical Applications**

- Solar Inverters
- Uninterruptible Power Supples (UPS)
- Motor Drives

#### **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector-emitter voltage	$V_{CES}$	600	V
Collector current @ Tc = 25°C @ Tc = 100°C	I <sub>C</sub>	100 50	Α
Pulsed collector current, T <sub>pulse</sub> limited by T <sub>Jmax</sub>	I <sub>CM</sub>	200	Α
Diode Forward Current @ Tc = 25°C @ Tc = 100°C	I <sub>F</sub>	100 50	Α
Diode Pulsed Current T <sub>pulse</sub> limited by T <sub>Jmax</sub>	I <sub>FM</sub>	200	Α
Short–circuit withstand time $V_{GE}$ = 15 V, $V_{CE}$ = 300 V, $T_{J} \le +150^{\circ}C$	t <sub>SC</sub>	5	μS
Gate-emitter voltage Transient Gate-Emitter Voltage	$V_{\sf GE}$	±20 ±30	V
Power Dissipation @ Tc = 25°C @ Tc = 100°C	P <sub>D</sub>	223 89	W
Operating junction temperature range	TJ	-55 to +150	°C
Storage temperature range	T <sub>stg</sub>	-55 to +150	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T <sub>SLD</sub>	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

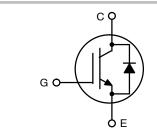


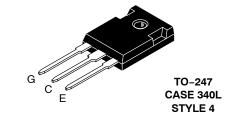
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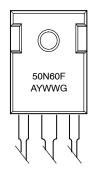
50 A, 600 V V<sub>CEsat</sub> = 1.45 V

 $E_{OFF} = 1.20 \text{ mJ}$ 





#### **MARKING DIAGRAM**



A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

#### **ORDERING INFORMATION**

Device	Package	Shipping
NGTB50N60FWG	TO-247 (Pb-Free)	30 Units / Rail

### THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ heta JC}$	0.56	°C/W
Thermal resistance junction-to-case, for Diode	$R_{ heta JC}$	0.74	°C/W
Thermal resistance junction-to-ambient	$R_{ hetaJA}$	40	°C/W

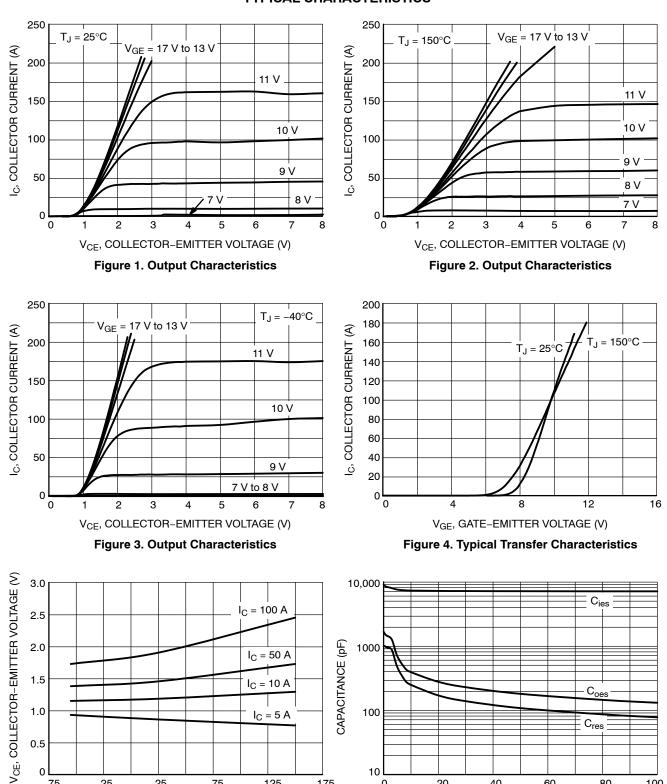
## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC	•	-		-		-
Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE} = 0 \text{ V}, I_{C} = 500 \mu A$	V <sub>(BR)CES</sub>	600	_	-	V
Collector-emitter saturation voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 50 A V <sub>GE</sub> = 15 V, I <sub>C</sub> = 50 A, T <sub>J</sub> = 150°C	V <sub>CEsat</sub>	1.25 –	1.45 1.7	1.7 -	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}$ , $I_C = 350 \mu A$	$V_{GE(th)}$	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 600 V V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 600 V, T <sub>J =</sub> 150°C	I <sub>CES</sub>	-	- -	0.5 2	mA
Gate leakage current, collector-emitter short-circuited	V <sub>GE</sub> = 20 V , V <sub>CE</sub> = 0 V	I <sub>GES</sub>	-	-	200	nA
DYNAMIC CHARACTERISTIC						
Input capacitance		C <sub>ies</sub>	-	7300	-	pF
Output capacitance	V <sub>CE</sub> = 20 V, V <sub>GE</sub> = 0 V, f = 1 MHz	C <sub>oes</sub>	_	275	-	
Reverse transfer capacitance	]	C <sub>res</sub>	_	170	-	
Gate charge total		Qg	-	310	-	nC
Gate to emitter charge	$V_{CE}$ = 480 V, $I_{C}$ = 50 A, $V_{GE}$ = 15 V	Q <sub>ge</sub>	-	60	_	
Gate to collector charge		$Q_{gc}$	-	150	-	
SWITCHING CHARACTERISTIC, INDUC	TIVE LOAD					=
Turn-on delay time		t <sub>d(on)</sub>	ı	117	-	ns
Rise time		t <sub>r</sub>	-	43	-	
Turn-off delay time	T <sub>J</sub> = 25°C	t <sub>d(off)</sub>	-	285	-	
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 50 \text{ A}$ $R_{c} = 10 \Omega$	t <sub>f</sub>	-	105	_	
Turn-on switching loss	$R_g = 10 \Omega$ $V_{GE} = 0 \text{ V/ } 15 \text{ V}$	E <sub>on</sub>	-	1.1	-	mJ
Turn-off switching loss		E <sub>off</sub>	-	1.2	-	
Total switching loss		E <sub>ts</sub>	-	2.3	-	
Turn-on delay time		t <sub>d(on)</sub>	-	112	_	ns
Rise time	1	t <sub>r</sub>	-	45	_	
Turn-off delay time	T <sub>J</sub> = 150°C	t <sub>d(off)</sub>	-	300	-	
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 50 \text{ A}$ $R_{g} = 10 \Omega$	t <sub>f</sub>	-	214	-	
Turn-on switching loss	V <sub>GE</sub> = 0 V/ 15 V	E <sub>on</sub>	_	1.4	-	mJ
Turn-off switching loss	]	E <sub>off</sub>	_	2.0	-	
Total switching loss	7	E <sub>ts</sub>	-	3.4	_	

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter Test Conditions		Symbol	Min	Тур	Max	Unit
DIODE CHARACTERISTIC						
Forward voltage	V <sub>GE</sub> = 0 V, I <sub>F</sub> = 50 A V <sub>GE</sub> = 0 V, I <sub>F</sub> = 50 A, T <sub>J</sub> = 150°C	V <sub>F</sub>	1.4 -	1.95 2.1	2.5 -	V
Reverse recovery time	T <sub>.I</sub> = 25°C	t <sub>rr</sub>	-	77	-	ns
Reverse recovery charge	$I_F = 50 \text{ Å}, V_R = 200 \text{ V}$	Q <sub>rr</sub>	-	0.4	-	μС
Reverse recovery current	di <sub>F</sub> /dt = 200 A/μs	I <sub>rrm</sub>	_	8	_	Α

#### **TYPICAL CHARACTERISTICS**



175

-75

25

T<sub>J</sub>, JUNCTION TEMPERATURE (°C)

Figure 5. V<sub>CE(sat)</sub> vs. T<sub>J</sub>

75

125

10

40

V<sub>CE</sub>, COLLECTOR-EMITTER VOLTAGE (V) Figure 6. Typical Capacitance

60

100

#### **TYPICAL CHARACTERISTICS**

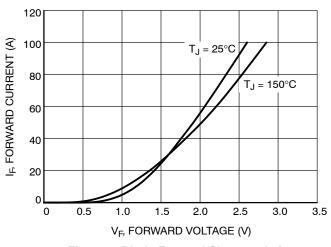


Figure 7. Diode Forward Characteristics

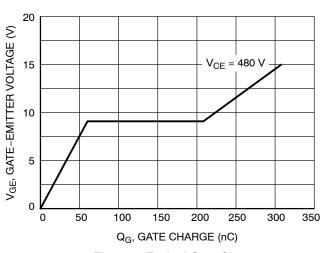


Figure 8. Typical Gate Charge

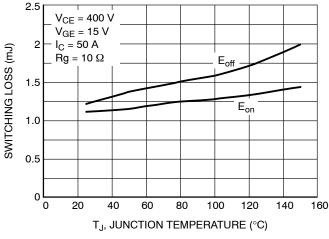


Figure 9. Switching Loss vs. Temperature

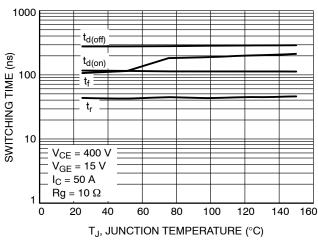


Figure 10. Switching Time vs. Temperature

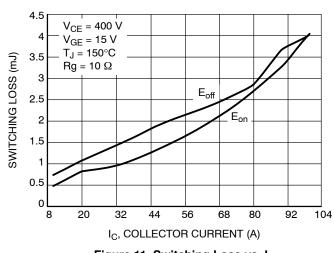


Figure 11. Switching Loss vs.  $I_{\text{C}}$ 

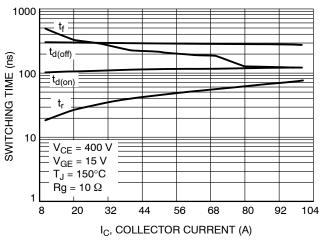
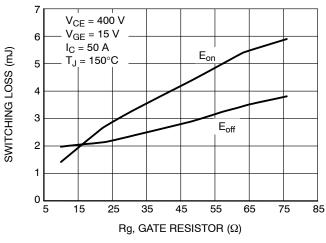


Figure 12. Switching Time vs. I<sub>C</sub>

#### **TYPICAL CHARACTERISTICS**



10,000

(E) 1000

(E) 1000

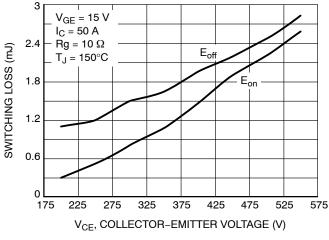
(E) 1000

(E) 1000

(F) 100

Figure 13. Switching Loss vs. Rg

Figure 14. Switching Time vs. Rg



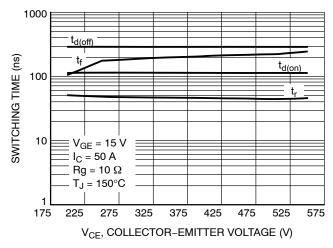
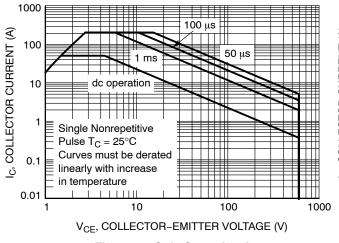


Figure 15. Switching Loss vs. V<sub>CE</sub>

Figure 16. Switching Time vs. V<sub>CE</sub>



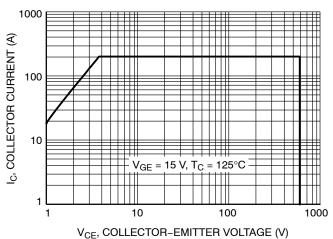


Figure 17. Safe Operating Area

Figure 18. Reverse Bias Safe Operating Area

#### **TYPICAL CHARACTERISTICS**

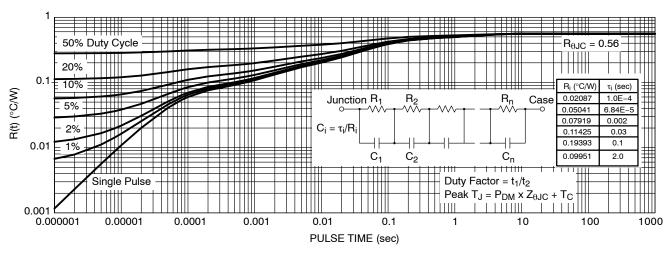


Figure 19. IGBT Transient Thermal Impedance

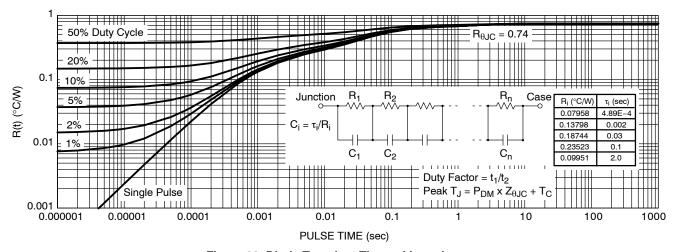


Figure 20. Diode Transient Thermal Impedance

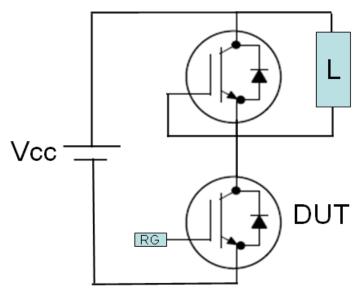


Figure 21. Test Circuit for Switching Characteristics

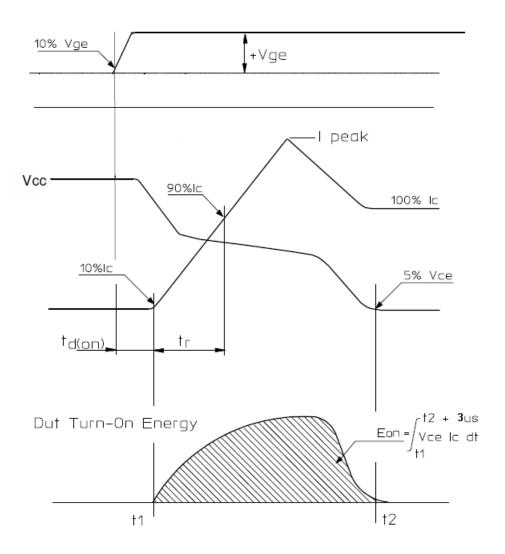


Figure 22. Definition of Turn On Waveform

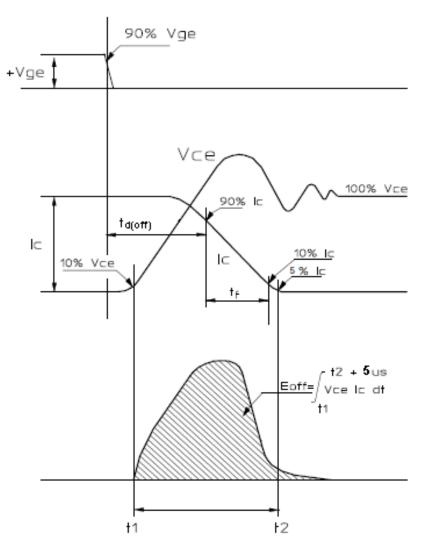
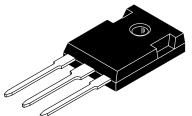


Figure 23. Definition of Turn Off Waveform





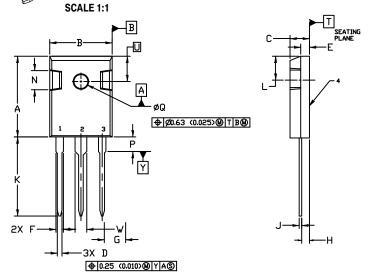
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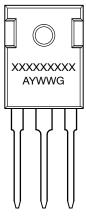
#### NOTES

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1982.
- 2. CONTROLLING DIMENSION: MILLIMETER

	MILLIMETERS		INC	HES
DIM	MIN.	MAX.	MIN.	MAX.
Α	20.32	21.08	0.800	0.830
В	15.75	16.26	0.620	0.640
С	4.70	5.30	0.185	0.209
D	1.00	1.40	0.040	0.055
Ε	1.90	2.60	0.075	0.102
F	1.65	2.13	0.065	0.084
G	5.45 BSC		0.215 BSC	
Н	1.50	2.49	0.059	0.098
J	0.40	0.80	0.016	0.031
К	19.81	20.83	0.780	0.820
L	5.40	6.20	0.212	0.244
N	4.32	5.49	0.170	0.216
Р		4.50		0.177
Q	3.55	3.65	0.140	0.144
U	6.15 BSC		0.242 BSC	
W	2.87	3.12	0.113	0.123



# GENERIC MARKING DIAGRAM\*



STYLE 1:	
PIN 1.	GATE
2.	DRAIN
3.	SOURCE
4.	DRAIN

STYLE 2:
PIN 1. ANODE
2. CATHODE (S)
3. ANODE 2
4. CATHODES (S)

STYLE 3:
PIN 1. BASE
2. COLLECTOR
3. EMITTER
4. COLLECTOR

STYLE 4:
PIN 1. GATE
2. COLLECTOR
3. EMITTER
4. COLLECTOR

XXXXX = Specific Device Code A = Assembly Location

Y = Year
WW = Work Week
G = Pb-Free Package

 STYLE 5:
 STYLE 6:

 PIN 1. CATHODE
 PIN 1. MAIN TERMINAL 1

 2. ANODE
 2. MAIN TERMINAL 2

 3. GATE
 3. GATE

 4. ANODE
 4. MAIN TERMINAL 2

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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